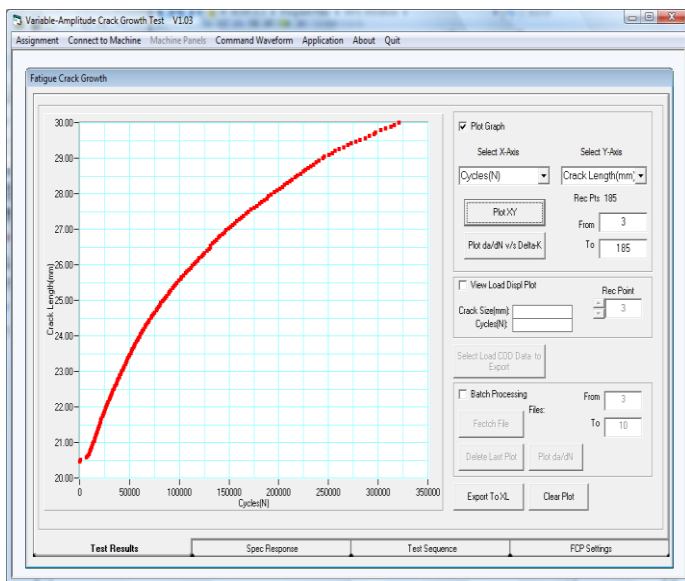


BISS CCG test application software is designed to perform Creep crack growth test using DCPD/COD/Remote Compliance under MTL32 environment with 2370 controller.

Creep Crack Growth test and creep fatigue crack growth tests as per ASTM E1457 & ASTM E2760 standards on various specimens like C(T) LLD, C(T) MOD etc.

CCG & CFCG rate Parameters and data as per the ASTM E 1457 & E 2760 standard



Technical features

- Application software fully automated for Windows 10
- Crack length measurement from unloading compliance
- Works with standard geometries including C(T)LLD, C(T)MOD etc.
- Integrated with DCPD for changing the constant set current and pulsing intervals
- Continuous or pulsed mode through software is available to change online
- Logs voltage signal from the C(T) sample through DCPD unit
- Test control with Constant Load
- Predefined Waveforms are Sine, Triangular & Trapezoidal
- Option for continuous and pulsed mode operation, that can be changed online
- Data exporting / backing up at pre-set time intervals during the test
- Results include crack size vs time, LLD vs Time, C^* , da/dt
- Option to change sampling interval any time during the test
- Test termination conditions includes limit on crack length, crack increment, K_{max}
- On-line graphs (X-Y, double Y, trend, chart recorder)
- LLD & DCPD data storage
- Temperature vs time data saved for max of six temperature sensors
- Option to save the test profiles
- Auto data acquisition settings
- Autoscaling of graphs
- Option to enter material properties and specimen dimensions
- Option to log temperature data
- Report & Data export in MS-Excel

Note: Specifications are subject to change without prior notice